

**Search Notes**

Application/Control No.

10/507,419

Examiner

Randolph Chu

Applicant(s)/Patent under  
Reexamination

BAYER ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
382	285	5/24/2007	RIC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	5/24/2007	RIC
Inventor Name Search	5/24/2007	RIC
NPL (internet)	5/24/2007	RIC
Consult with Wenpeng Chen	5/24/2007	RIC